



**THE DATASHEET OF  
HUF76429D3ST**



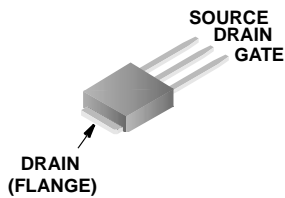
**20A, 60V, 0.027 Ohm, N-Channel, Logic Level UltraFET® Power MOSFET**



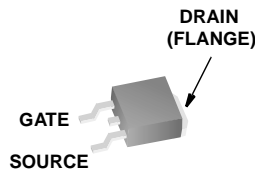
**Packaging**

JEDEC TO-251AA

JEDEC TO-252AA

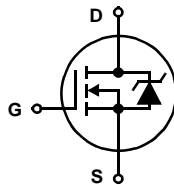


HUF76429D3



HUF76429D3S

**Symbol**



**Features**

- Ultra Low On-Resistance
  - $r_{DS(ON)} = 0.023\Omega$ ,  $V_{GS} = 10V$
  - $r_{DS(ON)} = 0.027\Omega$ ,  $V_{GS} = 5V$
- Simulation Models
  - Temperature Compensated PSPICE® and SABER™ Electrical Models
  - Spice and SABER Thermal Impedance Models
  - www.fairchildsemi.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Switching Time vs  $R_{GS}$  Curves

**Ordering Information**

PART NUMBER	PACKAGE	BRAND
HUF76429D3	TO-251AA	76429D
HUF76429D3S	TO-252AA	76429D

NOTE: When ordering, use the entire part number. Add the suffix T to obtain the variant in tape and reel, e.g., HUF76429D3ST.

**Absolute Maximum Ratings**  $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

	HUF76429D3, HUF76429D3S	UNITS
Drain to Source Voltage (Note 1)	$V_{DSS}$ 60	V
Drain to Gate Voltage ( $R_{GS} = 20k\Omega$ ) (Note 1)	$V_{DGR}$ 60	V
Gate to Source Voltage	$V_{GS}$ $\pm 16$	V
Drain Current		A
Continuous ( $T_C = 25^\circ\text{C}$ , $V_{GS} = 5V$ )	$I_D$ 20	A
Continuous ( $T_C = 25^\circ\text{C}$ , $V_{GS} = 10V$ ) (Figure 2)	$I_D$ 20	A
Continuous ( $T_C = 100^\circ\text{C}$ , $V_{GS} = 5V$ )	$I_D$ 20	A
Continuous ( $T_C = 100^\circ\text{C}$ , $V_{GS} = 4.5V$ ) (Figure 2)	$I_D$ 20	A
Pulsed Drain Current	$I_{DM}$ Figure 4	A
Pulsed Avalanche Rating	UIS Figures 6, 17, 18	
Power Dissipation	$P_D$ 110	W
Derate Above $25^\circ\text{C}$	0.74	W/ $^\circ\text{C}$
Operating and Storage Temperature	$T_J, T_{STG}$ -55 to 175	$^\circ\text{C}$
Maximum Temperature for Soldering		$^\circ\text{C}$
Leads at 0.063in (1.6mm) from Case for 10s.	$T_L$ 300	$^\circ\text{C}$
Package Body for 10s, See Techbrief TB334.	$T_{pkg}$ 260	$^\circ\text{C}$

NOTES:

1.  $T_J = 25^\circ\text{C}$  to  $150^\circ\text{C}$ .

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

Product reliability information can be found at <http://www.fairchildsemi.com/products/discrete/reliability/index.html>

For severe environments, see our Automotive HUFA series.

All Fairchild semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

# HUF76429D3, HUF76429D3S

## Electrical Specifications $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
<b>OFF STATE SPECIFICATIONS</b>							
Drain to Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$ (Figure 12)	60	-	-	V	
		$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$ , $T_C = -40^\circ\text{C}$ (Figure 12)	55	-	-	V	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 55\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$	
		$V_{DS} = 50\text{V}$ , $V_{GS} = 0\text{V}$ , $T_C = 150^\circ\text{C}$	-	-	250	$\mu\text{A}$	
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 16\text{V}$	-	-	$\pm 100$	nA	
<b>ON STATE SPECIFICATIONS</b>							
Gate to Source Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$ (Figure 11)	1	-	3	V	
Drain to Source On Resistance	$r_{DS(ON)}$	$I_D = 20\text{A}$ , $V_{GS} = 10\text{V}$ (Figures 9, 10)	-	0.0205	0.023	$\Omega$	
		$I_D = 20\text{A}$ , $V_{GS} = 5\text{V}$ (Figure 9)	-	0.024	0.027	$\Omega$	
		$I_D = 20\text{A}$ , $V_{GS} = 4.5\text{V}$ (Figure 9)	-	0.025	0.029	$\Omega$	
<b>THERMAL SPECIFICATIONS</b>							
Thermal Resistance Junction to Case	$R_{\theta JC}$	TO-251 and TO-252	-	-	1.36	$^\circ\text{C/W}$	
Thermal Resistance Junction to Ambient	$R_{\theta JA}$		-	-	100	$^\circ\text{C/W}$	
<b>SWITCHING SPECIFICATIONS (<math>V_{GS} = 4.5\text{V}</math>)</b>							
Turn-On Time	$t_{ON}$	$V_{DD} = 30\text{V}$ , $I_D = 20\text{A}$ $V_{GS} = 4.5\text{V}$ , $R_{GS} = 7.5\Omega$ (Figures 15, 21, 22)	-	-	220	ns	
Turn-On Delay Time	$t_{d(ON)}$		-	13	-	ns	
Rise Time	$t_r$		-	134	-	ns	
Turn-Off Delay Time	$t_{d(OFF)}$		-	30	-	ns	
Fall Time	$t_f$		-	55	-	ns	
Turn-Off Time	$t_{OFF}$		-	-	130	ns	
<b>SWITCHING SPECIFICATIONS (<math>V_{GS} = 10\text{V}</math>)</b>							
Turn-On Time	$t_{ON}$	$V_{DD} = 30\text{V}$ , $I_D = 20\text{A}$ $V_{GS} = 10\text{V}$ , $R_{GS} = 8.2\Omega$ (Figures 16, 21, 22)	-	-	65	ns	
Turn-On Delay Time	$t_{d(ON)}$		-	7.7	-	ns	
Rise Time	$t_r$		-	36	-	ns	
Turn-Off Delay Time	$t_{d(OFF)}$		-	60	-	ns	
Fall Time	$t_f$		-	56	-	ns	
Turn-Off Time	$t_{OFF}$		-	-	175	ns	
<b>GATE CHARGE SPECIFICATIONS</b>							
Total Gate Charge	$Q_{g(TOT)}$	$V_{GS} = 0\text{V to } 10\text{V}$	$V_{DD} = 30\text{V}$ , $I_D = 20\text{A}$ , $I_{g(REF)} = 1.0\text{mA}$ (Figures 14, 19, 20)	-	38	46	nC
Gate Charge at 5V	$Q_{g(5)}$	$V_{GS} = 0\text{V to } 5\text{V}$		-	21	25	nC
Threshold Gate Charge	$Q_{g(TH)}$	$V_{GS} = 0\text{V to } 1\text{V}$		-	1.3	1.6	nC
Gate to Source Gate Charge	$Q_{gs}$			-	3.8	-	nC
Gate to Drain "Miller" Charge	$Q_{gd}$			-	9.7	-	nC
<b>CAPACITANCE SPECIFICATIONS</b>							
Input Capacitance	$C_{ISS}$	$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1\text{MHz}$ (Figure 13)	-	1480	-	pF	
Output Capacitance	$C_{OSS}$		-	440	-	pF	
Reverse Transfer Capacitance	$C_{RSS}$		-	90	-	pF	

## Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	$V_{SD}$	$I_{SD} = 20\text{A}$	-	-	1.25	V
		$I_{SD} = 10\text{A}$	-	-	1.00	V
Reverse Recovery Time	$t_{rr}$	$I_{SD} = 20\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	80	ns
Reverse Recovered Charge	$Q_{RR}$	$I_{SD} = 20\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	230	nC

Typical Performance Curves

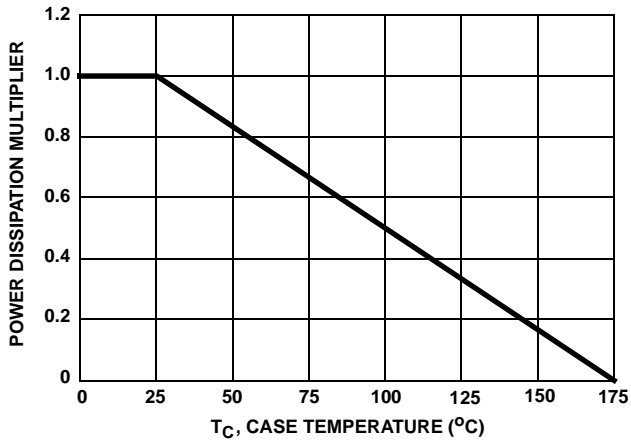


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

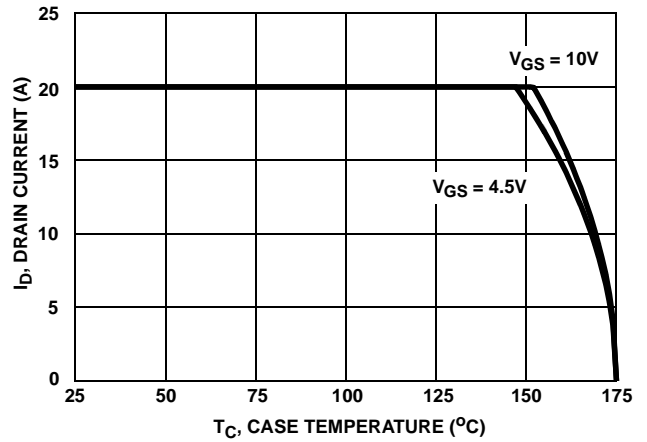


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

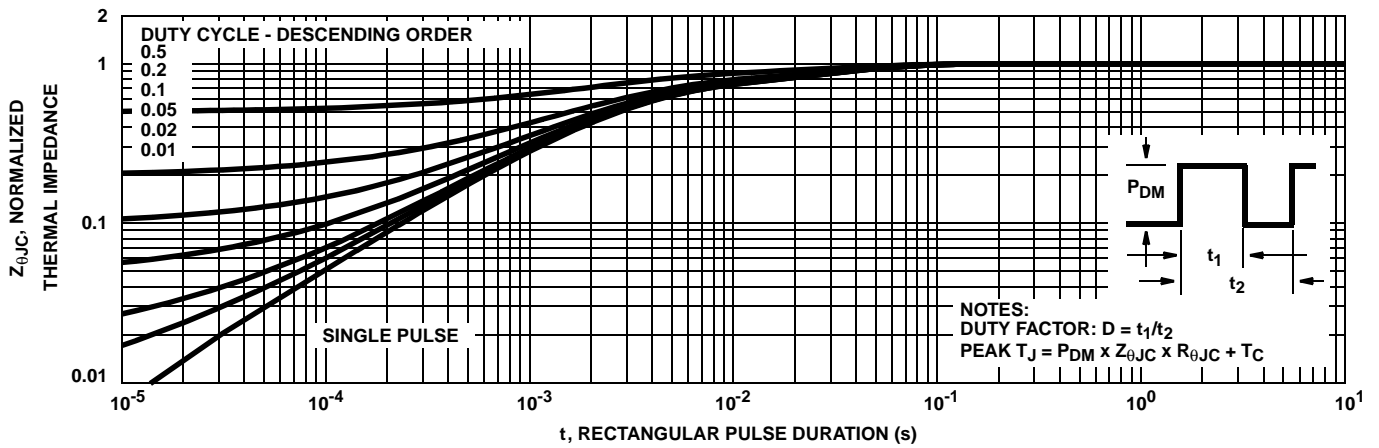


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

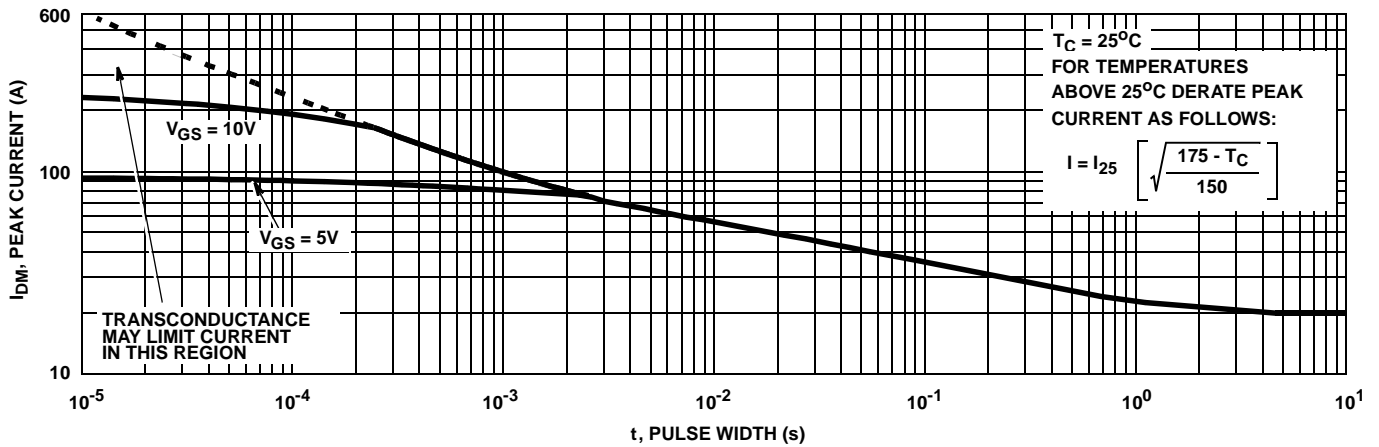


FIGURE 4. PEAK CURRENT CAPABILITY

Typical Performance Curves (Continued)

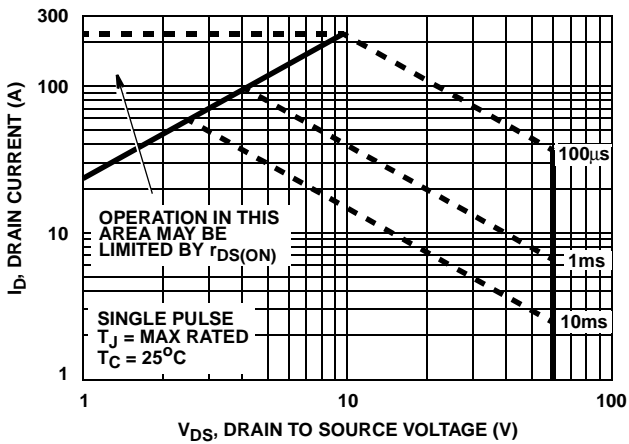
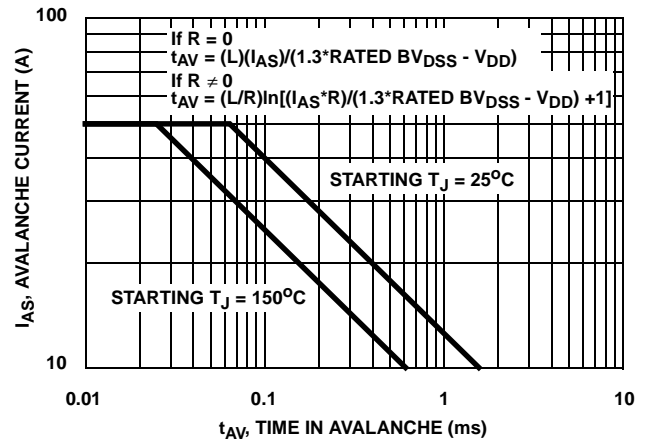


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA



NOTE: Refer to Fairchild Application Notes AN9321 and AN9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

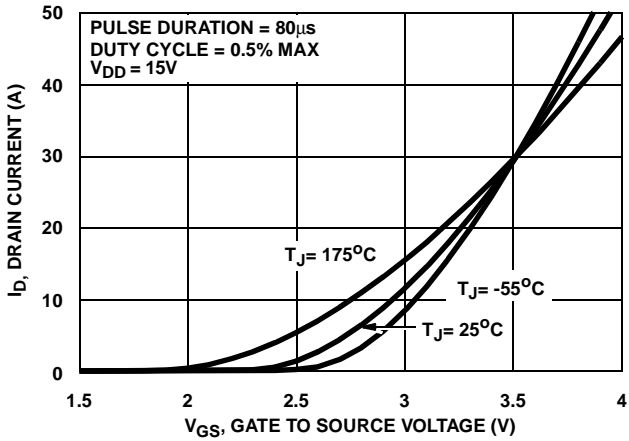


FIGURE 7. TRANSFER CHARACTERISTICS

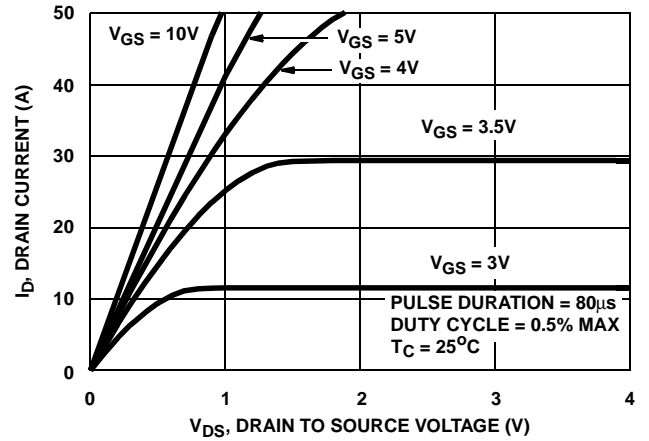


FIGURE 8. SATURATION CHARACTERISTICS

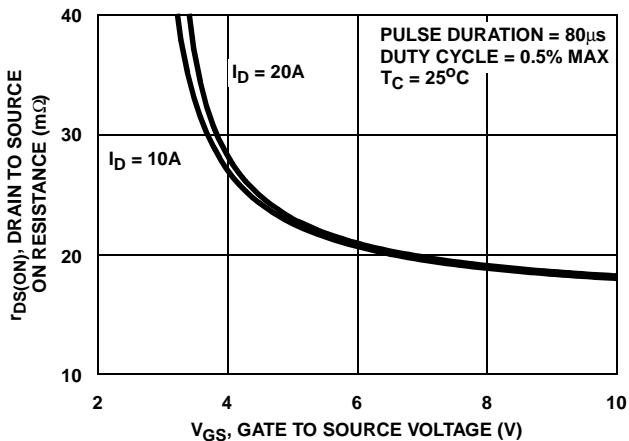


FIGURE 9. DRAIN TO SOURCE ON RESISTANCE vs. GATE VOLTAGE AND DRAIN CURRENT

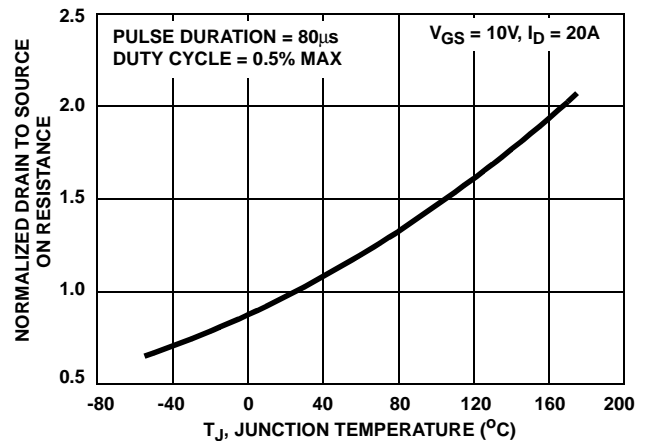


FIGURE 10. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs. JUNCTION TEMPERATURE

Typical Performance Curves (Continued)

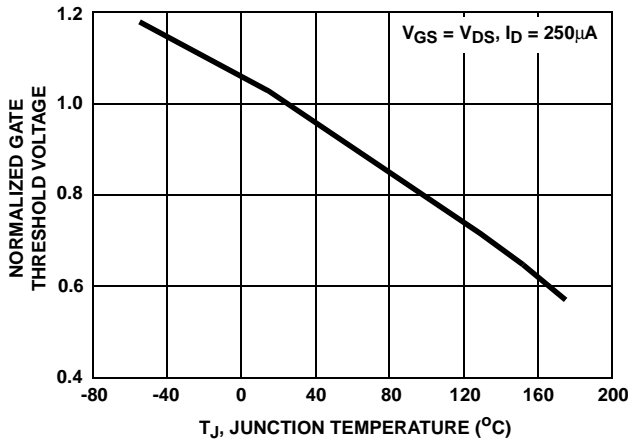


FIGURE 11. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

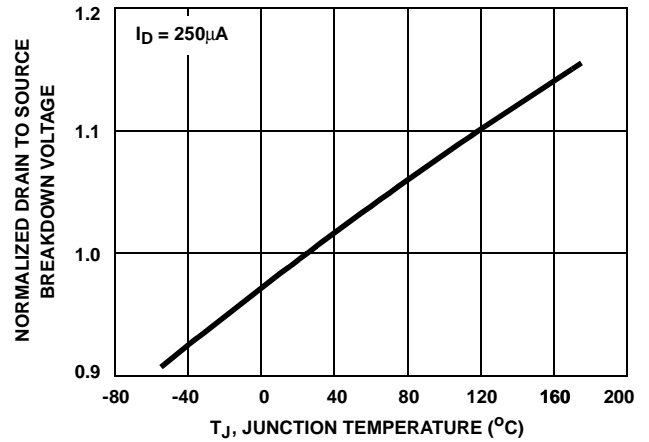


FIGURE 12. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

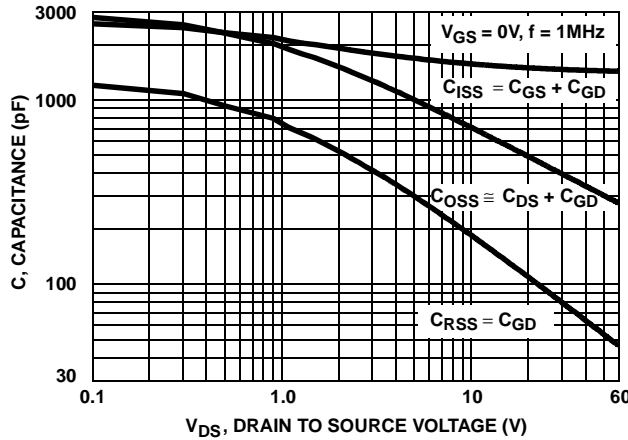
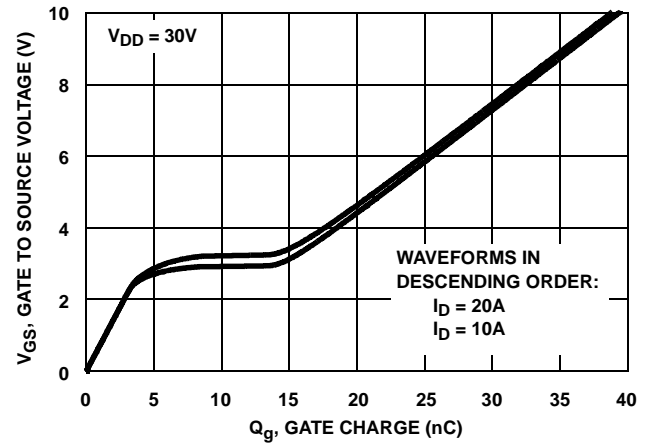


FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260.

FIGURE 14. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

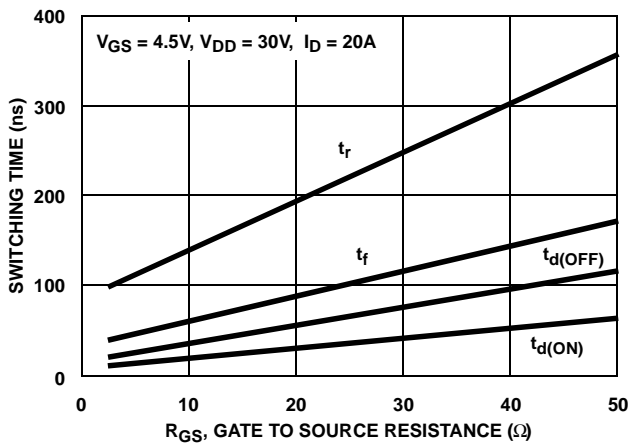


FIGURE 15. SWITCHING TIME vs GATE RESISTANCE

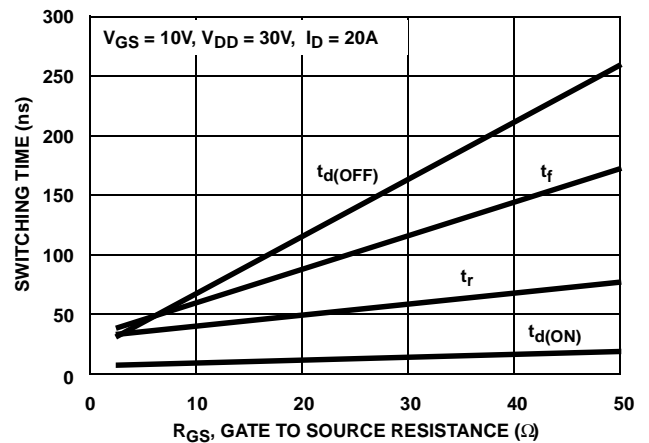


FIGURE 16. SWITCHING TIME vs GATE RESISTANCE

Test Circuits and Waveforms

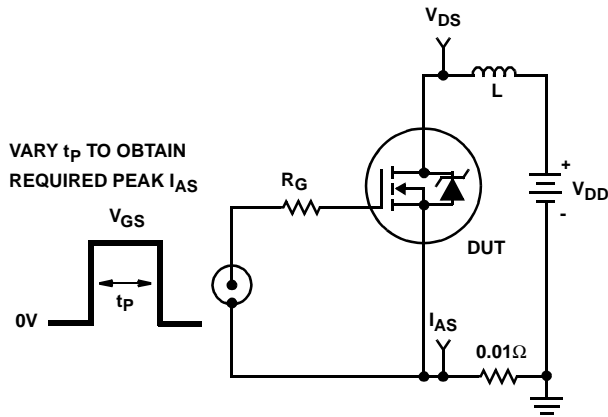


FIGURE 17. UNCLAMPED ENERGY TEST CIRCUIT

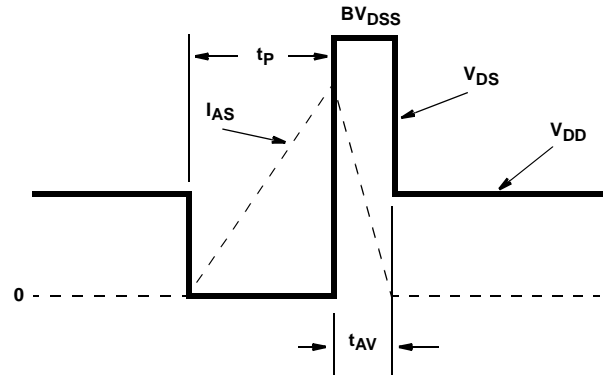


FIGURE 18. UNCLAMPED ENERGY WAVEFORMS

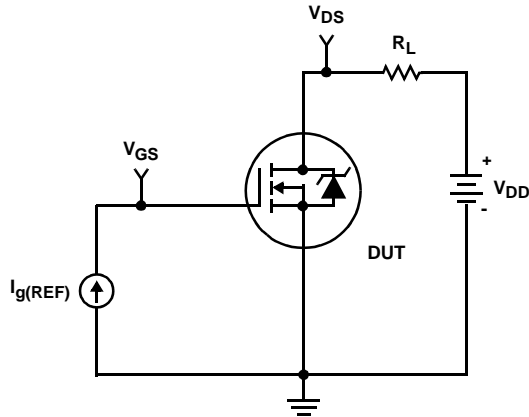


FIGURE 19. GATE CHARGE TEST CIRCUIT

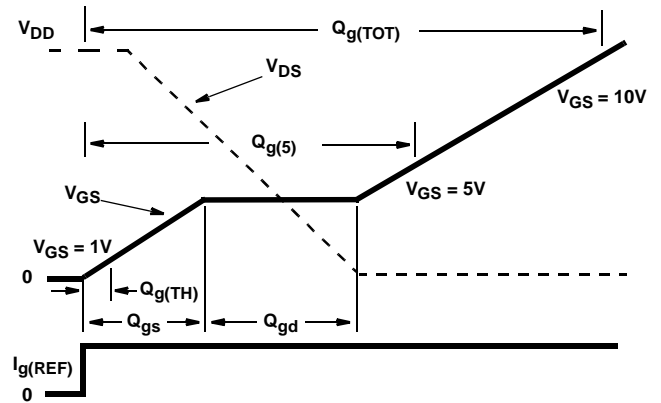


FIGURE 20. GATE CHARGE WAVEFORMS

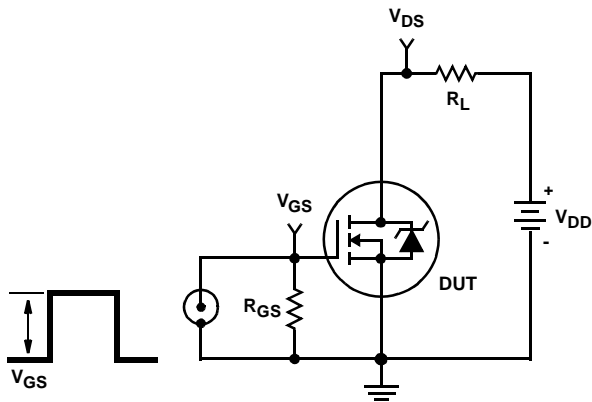


FIGURE 21. SWITCHING TIME TEST CIRCUIT

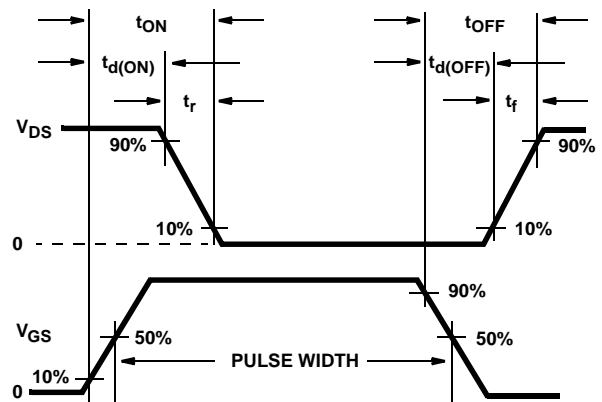


FIGURE 22. SWITCHING TIME WAVEFORM





**SPICE Thermal Model**

REV 26 July 1999

HUF76429D3

CTHERM1 th 6 2.45e-3  
 CTHERM2 6 5 8.15e-3  
 CTHERM3 5 4 7.40e-3  
 CTHERM4 4 3 7.45e-3  
 CTHERM5 3 2 1.01e-2  
 CTHERM6 2 tl 7.49e-2

RTHERM1 th 6 9.00e-3  
 RTHERM2 6 5 1.80e-2  
 RTHERM3 5 4 9.15e-2  
 RTHERM4 4 3 2.43e-1  
 RTHERM5 3 2 3.50e-1  
 RTHERM6 2 tl 3.62e-1

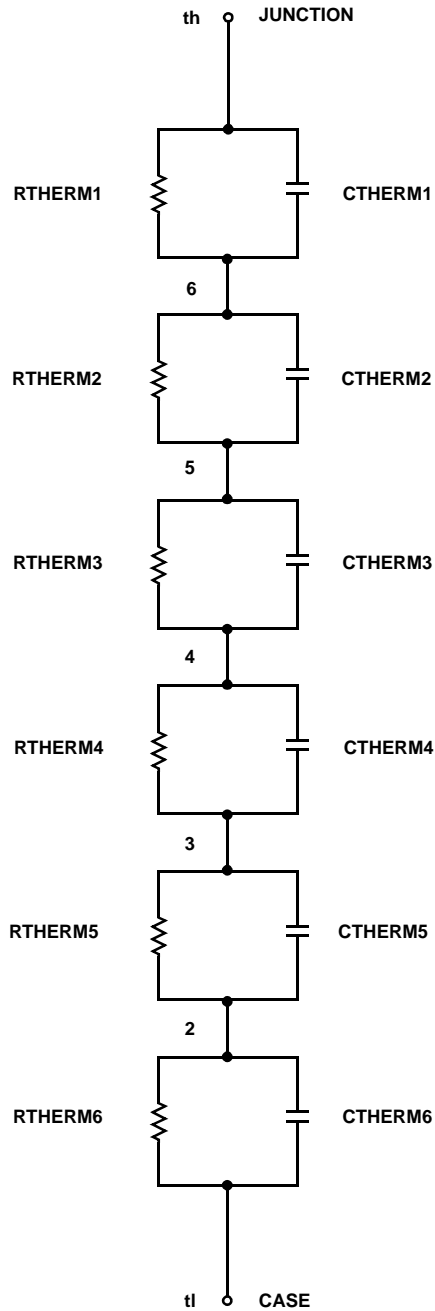
**SABER Thermal Model**

SABER thermal model HUF76429D3

```

template thermal_model th tl
thermal_c th, tl
{
    ctherm.ctherm1 th 6 = 2.45e-3
    ctherm.ctherm2 6 5 = 8.15e-3
    ctherm.ctherm3 5 4 = 7.40e-3
    ctherm.ctherm4 4 3 = 7.45e-3
    ctherm.ctherm5 3 2 = 1.01e-2
    ctherm.ctherm6 2 tl = 7.49e-2

    rtherm.rtherm1 th 6 = 9.00e-3
    rtherm.rtherm2 6 5 = 1.80e-2
    rtherm.rtherm3 5 4 = 9.15e-2
    rtherm.rtherm4 4 3 = 2.43e-1
    rtherm.rtherm5 3 2 = 3.50e-1
    rtherm.rtherm6 2 tl = 3.62e-1
}
    
```



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CoolFET™	FRFET™	MICROCOUPLER™	PowerSaver™	SuperSOT™-3
CROSSVOLT™	GlobalOptoisolator™	MicroFET™	PowerTrench®	SuperSOT™-6
DOMET™	GTO™	MicroPak™	QFET®	SuperSOT™-8
EcoSPARK™	HiSeC™	MICROWIRE™	QS™	SyncFET™
E <sup>2</sup> CMOS™	ꝑC™	MSX™	QT Optoelectronics™	TinyLogic®
EnSigna™	i-Lo™	MSXPro™	Quiet Series™	TINYOPTO™
FACT™	ImpliedDisconnect™	OCX™	RapidConfigure™	TruTranslation™
FACT Quiet Series™		OCXPro™	RapidConnect™	UHC™
Across the board. Around the world.™		OPTOLOGIC®	µSerDes™	UltraFET®
The Power Franchise®		OPTOPLANAR™	SILENT SWITCHER®	UniFET™
Programmable Active Droop™		PACMAN™	SMART START™	VCX™

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### Definition of Terms

Datasheet Identification	Product Status	Definition
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